Special Issue

Recent Advances in Deep Learning for Image Analysis

Message from the Guest Editors

Recently, deep learning algorithms have been used for a wide range of computer vision and image analysis tasks. However, deep learning still poses some challenges in regard to training time, network size, accuracy, computing power, and overfitting. These challenges need to be addressed in order to provide reliable and efficient deep learning networks. Hence, the aim of this Special Issue is to cover novel, optimized, high-performance, and hybrid deep-learning-based approaches for image analysis to address the aforementioned challenges in a variety of applications. Topics of interest include, but are not limited to, the following:

- Deep-learning-based image analysis in various disciplines.
- Image analysis using deep learning.
- Effective augmentation methods for deep-learning-based image analysis.
- Hybrid machine learning and deep learning methods for image analysis.
- Efficient deep learning architectures for image analysis.
- Deep learning models on mobile and embedded devices for image analysis.
- Transfer learning, domain adaptation, and knowledge distillation for image analysis.

Guest Editors

Prof. Dr. Tan-Hsu Tan

Prof. Dr. Mohammad Alkhaleefah

Prof. Dr. Yang-Lang Chang

Deadline for manuscript submissions

closed (31 October 2022)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/94647

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

mdpi.com/journal/applsci

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/journal/applsci

MDPI

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)